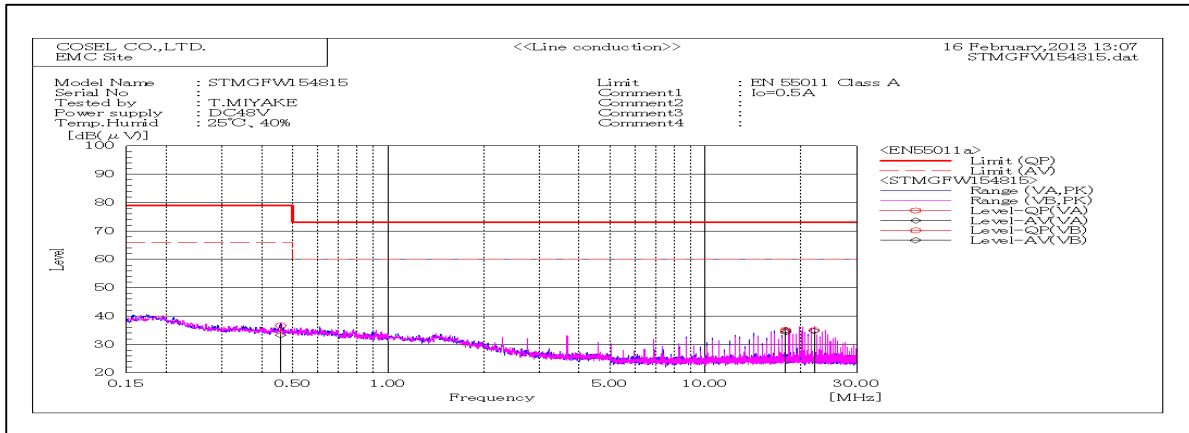
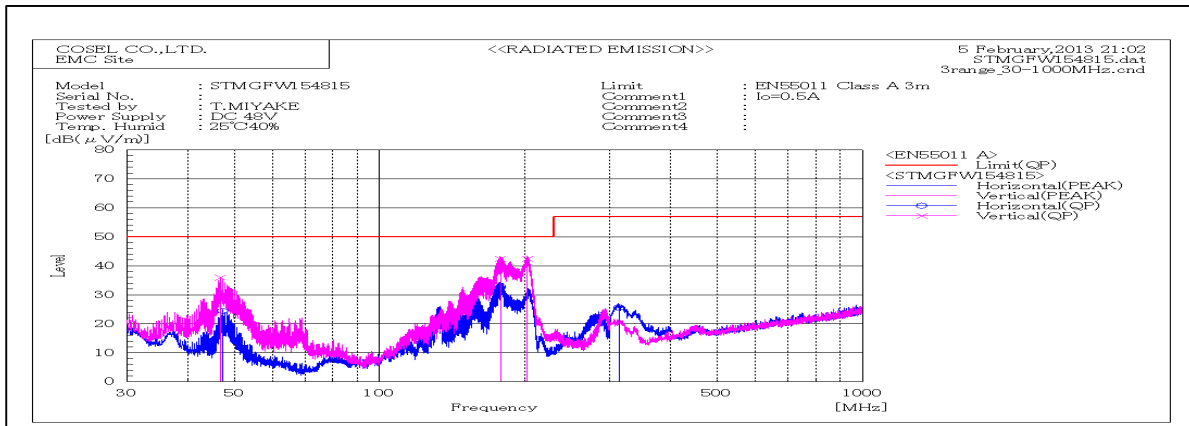


DATA SHEET		Date	18-Feb-13
Model	STMGFW154815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



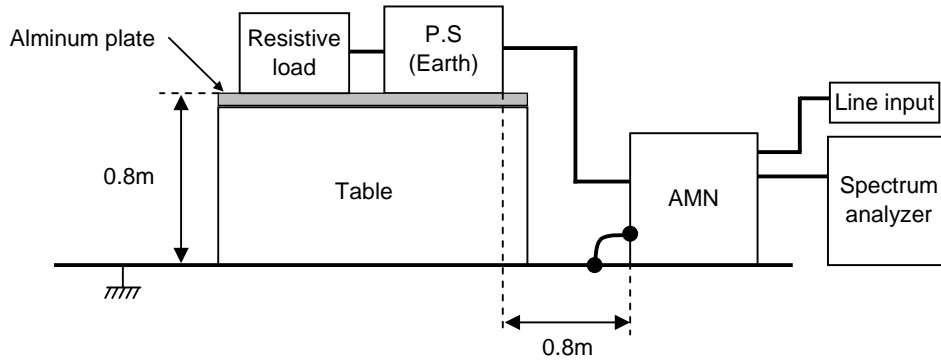
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45942		VA	16.6	13.2	20.1	36.7	33.3	79	66	42.3	32.7	Pass	
17.89555		VB	13.5	13.2	21.1	34.6	34.3	73	60	38.4	25.7	Pass	
17.8946		VA	13.9	13.8	21.2	35.1	35	73	60	37.9	25	Pass	
22.02165		VB	13.9	13.7	21.1	35	34.8	73	60	38	25.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP						
46.865	V	Stable	57.9	-21.9	36	50	14	Pass	101	334			
47.323	H	Stable	47.7	-23.3	24.4	50	25.6	Pass	156	110			
178.077	H	Stable	55	-22.3	32.7	50	17.3	Pass	158	268			
178.062	V	Stable	58.4	-16	42.4	50	7.6	Pass	103	305			
202.429	V	Stable	58.2	-15.8	42.4	50	7.6	Pass	102	291			
313.405	H	Stable	42.8	-17.2	25.6	57	31.4	Pass	108	88			

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

